

Search Notes

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Examiner

Joon H. Hwang

Applicant(s)/Patent under
Reexamination

DEGUCHI ET AL.

Art Unit

2166

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Palm See search history printout(s) consulted Jean M. Corrielus consulted Alford Kindred	6/1/2006	JH